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FORM PTO-14 TRADEN (Modified)

S.S. DEPAR MENT TO OMMERCE PATENT AND TRADEMARK OFFICE

DOCKET NO. **AWEK 2301**

APPLICATION NO. 09/941,485

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

FILING DATE August 28, 2001 **GROUP 1725**

APPLICANT Mikko VEIKKOLAINEN et al

(37 CFR 1.98(b))

		U.S. PAT					
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APPLICANT Mikko VEIKKOLAINEN et al

OCT 0 1 2002

FORM PTO-1449 (Modified)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use several sheets if necessary)

FILING DATE

GROUP 1725

(37 CFR 1.98(b))

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